

 <p>INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)</p>	Docket Number (Optional) TWI-10820	Application Number 09/629,407
	Applicant(s) Allan Rosencwaig et al.	
	Filing Date August 1, 2000	Group Art Unit 2876

U.S. PATENT DOCUMENTS

REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
BA						
BB						

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
HKS	BC	2720131	11/21/1997	Japan (w/translation)	G01N	23/207	X	
	BD							

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

HKS	BE	K. Sakurai et al., "Fourier Analysis of Interference Structure in X-Ray Specular Reflection from Thin Films," <i>Jpn. J. Appl. Phys.</i> , Vol. 31, 1992, pp. L113-L115.
	BF	K.N. Stoev et al., "Review on grazing incidence X-ray spectrometry and reflectometry," <i>Spectrochimica Acta Part B</i> , Vol. 54, 1999, pp. 41-82.
	BG	N. Wainfan et al., "Density Measurements of Some Thin Copper Films," <i>Journal of Applied Physics</i> , Vol. 30, No. 10, October 1959, pp. 1604-1609.
	BH	J.P. Sauro et al., "Some Observations on the Interference Fringes Formed by X Rays Scattered from Thin Films," <i>Physical Review</i> , Vol. 143, No. 1, March 1966, pp. 439-443.
	BI	K. Sakurai et al., Analysis of thin films by X-ray scattering at grazing incidence," <i>SPRING-8 User Experiment Report No. 2, (1998 A)</i> , March 1999, p. 162.
	BJ	L.G. Parratt, "Surface Studies of Solids by Total Reflection of X-Rays," <i>Physical Review</i> , Vol. 95, No. 2, July 15, 1954, pp. 359-369.
	BK	M.F. Toney, "Measurements of carbon thin films using x-ray reflectivity," <i>J. Appl. Phys.</i> , Vol. 66, No. 4, 15 August 1989, pp. 1861-1863.
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HKS	BO	E. Chason et al., "Energy Dispersive X-Ray Reflectivity Characterization of Semiconductor Heterostructures and Interfaces," <i>American Institute of Physics</i> , 1996, pp. 512-516.

Examiner HKS	Date Considered 2-19-02
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09/629,407

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PATENTSheet 1 of 1

FORM PTO-1449 (Modified) (Rev. 7-80)		U.S. Dept. of Commerce Patent and Trademark Office		Atty Docket No. TWI-10820		Appln. No. 09/629,407	
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)				Applicant(s) Allan Rosencwaig et al.		Group 2876	
				Filing Date August 1, 2000			
U.S. PATENT DOCUMENTS							
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date
HKS	AA	5,371,582	12/06/1994	Toba et al.	356	73	07/30/1993
	AB	5,619,548	04/08/1997	Koppel	378	70	08/11/1995
HKS	AC	5,740,226	04/14/1998	Komiya et al.	378	70	11/27/1996
	AD						
FOREIGN PATENT DOCUMENTS							
*Examiner Initials		Document Number	Date	Country	Class	Subclass	Translation YES NO
HKS	AE	0 352 740	07/25/1989	EPC	H01L	21/306	
HKS	AF	EP 0 768 512	10/15/1996	EPC	G01B	11/06	
	AG						
OTHER DOCUMENTS							
	AH						
	AI						
Examiner HKS				Date Considered 2-18-02			
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